HEF4024B

7-stage binary counter Rev. 7 — 18 November 2011

Product data sheet

General description 1.

The HEF4024B is a 7-stage binary ripple counter with a clock input (CP), and overriding asynchronous master reset input (MR) and seven fully buffered parallel outputs (Q0 to Q6). The counter advances on the HIGH to LOW transition of $\overline{\text{CP}}$. A HIGH on MR clears all counter stages and forces all outputs LOW, independent of CP. Each counter stage is a static toggle flip-flop.

It operates over a recommended V_{DD} power supply range of 3 V to 15 V referenced to V_{SS} (usually ground). Unused inputs must be connected to V_{DD}, V_{SS}, or another input.

Features and benefits 2.

- Tolerant of slow clock rise and fall time
- Fully static operation
- 5 V, 10 V, and 15 V parametric ratings
- Standardized symmetrical output characteristics
- Specified from –40 °C to +85 °C
- Complies with JEDEC standard JESD 13-B

Applications 3.

- Frequency dividers
- Time delay circuits

Ordering information 4.

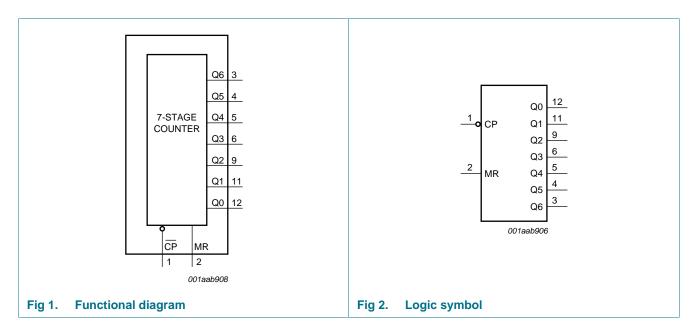
Table 1. **Ordering information**

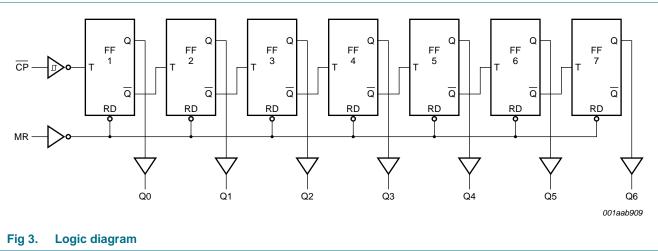
All types operate from −40 °C to +85 °C

Type number	Package					
	Name	Description	Version			
HEF4024BP	DIP14	plastic dual in-line package; 14 leads (300 mil)	SOT27-1			
HEF4024BT	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1			



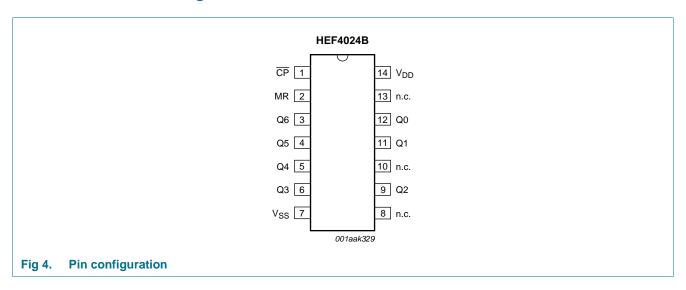
5. Functional diagram





6. Pinning information

6.1 Pinning



6.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
CP	1	clock input (HIGH to LOW edge-triggered)
MR	2	master reset input
V _{SS}	7	ground (0 V)
n.c.	8, 10, 13	not connected
Q0 to Q6	12, 11, 9, 6, 5, 4, 3,	buffered parallel outputs
V_{DD}	14	supply voltage

7. Functional description

Table 3. Functional table [1]

Input	Output	
Input CP	MR	Q0 to Q6
\uparrow	L	no change
→	L	count
X	Н	L

^[1] $H = HIGH \text{ voltage level; } L = LOW \text{ voltage level; } X = don't \text{ care; } \uparrow = positive-going transition; } \downarrow = negative-going transition.$

8. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DD}	supply voltage		-0.5	+18	V
I _{IK}	input clamping current	$V_I < -0.5 \text{ V or } V_I > V_{DD} + 0.5 \text{ V}$	-	±10	mA
V_{I}	input voltage		-0.5	$V_{DD} + 0.5$	V
I _{OK}	output clamping current	$V_O < -0.5 \text{ V or } V_O > V_{DD} + 0.5 \text{ V}$	-	±10	mA
I _{I/O}	input/output current		-	±10	mA
I _{DD}	supply current		-	50	mA
T _{stg}	storage temperature		-65	+150	°C
T _{amb}	ambient temperature	in free air	-40	+85	°C
P _{tot}	total power dissipation	T_{amb} –40 °C to +85 °C			
		DIP14 package	[1] -	750	mW
		SO14 package	[2] _	500	mW
Р	power dissipation	per output	-	100	mW

^[1] For DIP14 package: P_{tot} derates linearly with 12 mW/K above 70 °C.

9. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DD}	supply voltage		3	15	V
VI	input voltage		0	V_{DD}	V
T _{amb}	ambient temperature	in free air	-40	+85	°C
$\Delta t/\Delta V$	input transition rise and fall rate	$V_{DD} = 5 V$	-	3.75	μs/V
		V _{DD} = 10 V	-	0.5	μs/V
		V _{DD} = 15 V	-	0.08	μs/V

10. Static characteristics

Table 6. Static characteristics

 $V_{SS} = 0 \ V$; $V_I = V_{SS}$ or V_{DD} ; unless otherwise specified.

Symbol	Parameter	Conditions	Conditions V _{DD}	T _{amb} =	–40 °C	T _{amb} = 25 °C		T _{amb} = 85 °C		Unit
				Min	Max	Min	Max	Min	Max	
V_{IH}	HIGH-level input voltage	$ I_O < 1 \mu A$	5 V	3.5	-	3.5	-	3.5	-	V
			10 V	7.0	-	7.0	-	7.0	-	V
			15 V	11.0	-	11.0	-	11.0	-	V
V _{IL}	LOW-level input voltage	$ I_O < 1 \mu A$	5 V	-	1.5	-	1.5	-	1.5	V
			10 V	-	3.0	-	3.0	-	3.0	V
			15 V	-	4.0	-	4.0	-	4.0	V

HEF4024B

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^[2] For SO14 package: P_{tot} derates linearly with 8 mW/K above 70 °C.

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7-stage binary counter

 Table 6.
 Static characteristics ...continued

 $V_{SS} = 0$ V; $V_{I} = V_{SS}$ or V_{DD} ; unless otherwise specified.

Symbol	Parameter	Conditions	V_{DD}	T _{amb} =	-40 °C	$T_{amb} = 25 ^{\circ}C T_{amb}$		T _{amb} =	= 85 °C	Unit
				Min	Max	Min	Max	Min	Max	
V _{OH}	HIGH-level output voltage	$ I_{O} < 1 \mu A$	5 V	4.95	-	4.95	-	4.95	-	V
			10 V	9.95	-	9.95	-	9.95	-	V
			15 V	14.95	-	14.95	-	14.95	-	V
V _{OL}	LOW-level output voltage	$ I_{O} < 1 \mu A$	5 V	-	0.05	-	0.05	-	0.05	V
			10 V	-	0.05	-	0.05	-	0.05	V
			15 V	-	0.05	-	0.05	-	0.05	V
I _{OH}	HIGH-level output current	$V_0 = 2.5 \text{ V}$	5 V	-	-1.7	-	-1.4	-	-1.1	mΑ
		V _O = 4.6 V	5 V	-	-0.52	-	-0.44	-	-0.36	mΑ
		V _O = 9.5 V	10 V	-	-1.3	-	-1.1	-	-0.9	mΑ
		V _O = 13.5 V	15 V	-	-3.6	-	-3.0	-	-2.4	mΑ
I _{OL}	LOW-level output current	$V_0 = 0.4 \text{ V}$	5 V	0.52	-	0.44	-	0.36	-	mΑ
		$V_0 = 0.5 \text{ V}$	10 V	1.3	-	1.1	-	0.9	-	mΑ
		V _O = 1.5 V	15 V	3.6	-	3.0	-	2.4	-	mΑ
l _l	input leakage current		15 V	-	±0.3	-	±0.3	-	±1.0	μΑ
I _{DD}	supply current	I _O = 0 A	5 V	-	20	-	20	-	30	μΑ
			10 V	-	40	-	40	-	60	μΑ
			15 V	-	80	-	80	-	120	μΑ
C _I	input capacitance		-	-	-	-	7.5	-	-	pF

11. Dynamic characteristics

Table 7. Dynamic characteristics

 $V_{SS} = 0 \text{ V; } T_{amb} = 25 \text{ °C; for test circuit see }$ in less otherwise specified.

				•				
Symbol	Parameter	Conditions	V_{DD}	Extrapolation formula[1]	Min	Тур	Max	Unit
t _{PHL}	HIGH to LOW	CP®Q0;	5 V	73 ns + (0.55 ns/pF)C _L	-	100	200	ns
propaga	propagation delay	see <u>Figure 5</u>	10 V	29 ns + (0.23 ns/pF)C _L	-	40	75	ns
			15 V	17 ns + (0.16 ns/pF)C _L	-	25	50	ns
		$Qn \rightarrow Qn + 1;$	5 V	33 ns + (0.55 ns/pF)C _L	-	60	120	ns
		see <u>Figure 5</u>	10 V	14 ns + (0.23 ns/pF)C _L	-	25	50	ns
			15 V	12 ns + (0.16 ns/pF)C _L	-	20	40	ns
		$MR \rightarrow Qn;$ see Figure 5	5 V	93 ns + (0.55 ns/pF)C _L	-	120	240	ns
			10 V	34 ns + (0.23 ns/pF)C _L	-	45	90	ns
			15 V	22 ns + (0.16 ns/pF)C _L	-	30	60	ns
t _{PLH}	LOW to HIGH	CP®Q0;	5 V	78 ns + (0.55 ns/pF)C _L	-	105	210	ns
	propagation delay	see <u>Figure 5</u>	10 V	34 ns + (0.23 ns/pF)C _L	-	45	85	ns
			15 V	22 ns + (0.16 ns/pF)C _L	-	30	60	ns
		$Qn \rightarrow Qn + 1$ see Figure 5	5 V	23 ns + (0.55 ns/pF)C _L	-	50	100	ns
			10 V	9 ns + (0.23 ns/pF)C _L	-	20	40	ns
			15 V	7 ns + (0.16 ns/pF)C _L	-	15	30	ns

 Table 7.
 Dynamic characteristics ...continued

 $V_{SS} = 0 \text{ V; } T_{amb} = 25 \text{ °C; for test circuit see } \frac{\text{Figure 6}}{\text{circuit see }}; \text{ unless otherwise specified.}$

Symbol	Parameter	Conditions	V_{DD}	Extrapolation formula[1]	Min	Тур	Max	Unit
t _t	transition time	see Figure 5	5 V [2]	10 ns + (1.00 ns/pF)C _L	-	60	120	ns
			10 V	9 ns + (0.42 ns/pF)C _L	-	30	60	ns
			15 V	6 ns + (0.28 ns/pF)C _L	-	20	40	ns
t _W	pulse width	CP HIGH;	5 V		60	30	-	ns
		minimum width	10 V		30	15	-	ns
		see Figure 5	15 V		20	10	-	ns
		MR HIGH; minimum width see <u>Figure 5</u>	5 V		80	40	-	ns
			10 V		35	20	-	ns
			15 V		25	15	-	ns
t _{rec}	recovery time	MR;	5 V		20	10	-	ns
		see Figure 5	10 V		15	5	-	ns
			15 V		15	5	-	ns
f _{max}	maximum		5 V		5	10	-	MHz
	frequency		10 V		13	25	-	MHz
			15 V		18	35	-	MHz

^[1] The typical values of the propagation delay and transition times are calculated from the extrapolation formulas shown (C_L in pF).

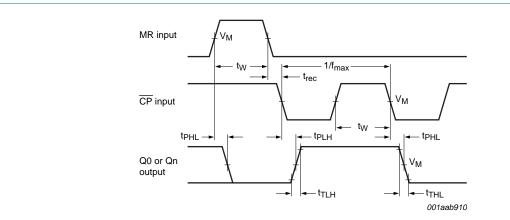
Table 8. Dynamic power dissipation P_D

 P_D can be calculated from the formulas shown. $V_{SS} = 0$ V; $t_r = t_f \le 20$ ns; $T_{amb} = 25$ °C.

Symbol	Parameter	V_{DD}	Typical formula for P_D (μ W)	Where:
P_{D}	dynamic power	5 V	$P_D = 500 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2$	f _i = input frequency in MHz;
	dissipation	10 V	$P_D = 2100 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2$	f _o = output frequency in MHz;
		15 V	$P_D = 5200 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2$	C_L = output load capacitance in pF;
				V _{DD} = supply voltage in V;
				$\Sigma(f_0 \times C_L)$ = sum of the outputs.

^[2] t_t is the same as t_{TLH} and t_{THL} .

12. Waveforms

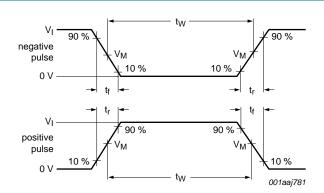


 V_{OH} and V_{OL} are typical output voltages levels that occur with the output load. Measurement points are given in Table 9.

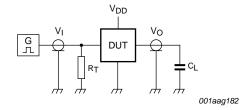
Fig 5. Waveforms showing propagation delays for MR to Qn and $\overline{\text{CP}}$ to Q0, minimum MR and $\overline{\text{CP}}$ pulse widths and recovery time for MR.

Table 9. Measurement points

Supply voltage	Input	Output
V_{DD}	V _M	V _M
5 V to 15 V	0.5V _{DD}	0.5V _{DD}



a. Input waveforms



b. Test circuit

Test data is given in <u>Table 10</u>.

Definitions for test circuit:

DUT = Device Under Test.

C_L = load capacitance including jig and probe capacitance.

 R_T = termination resistance should be equal to the output impedance Z_0 of the pulse generator.

Fig 6. Test circuit for measuring switching times

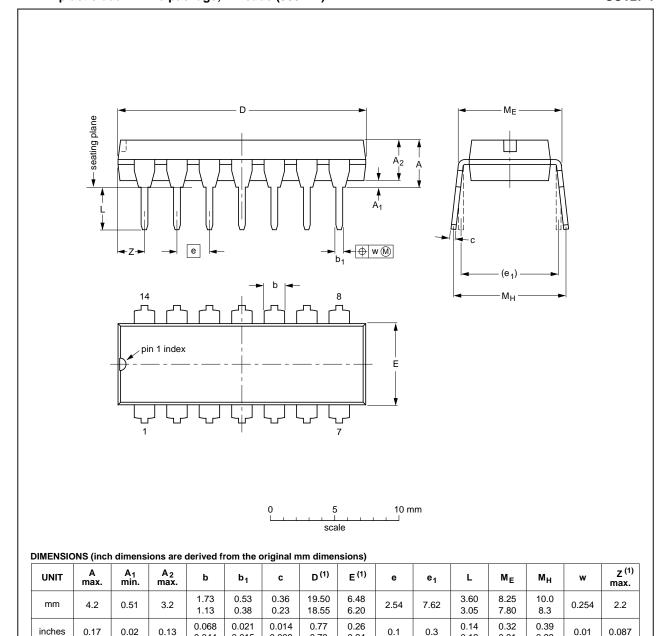
Table 10. Test data

Supply voltage	Input	Load	
V_{DD}	VI	t _r , t _f	CL
5 V to 15 V	V _{SS} or V _{DD}	≤ 20 ns	50 pF

13. Package outline

DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



Note

1. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

0.044

0.015

0.009

OUTLINE VERSION	REFERENCES			EUROPEAN	ISSUE DATE	
	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT27-1	050G04	MO-001	SC-501-14			99-12-27 03-02-13

0.73

0.24

0.12

0.31

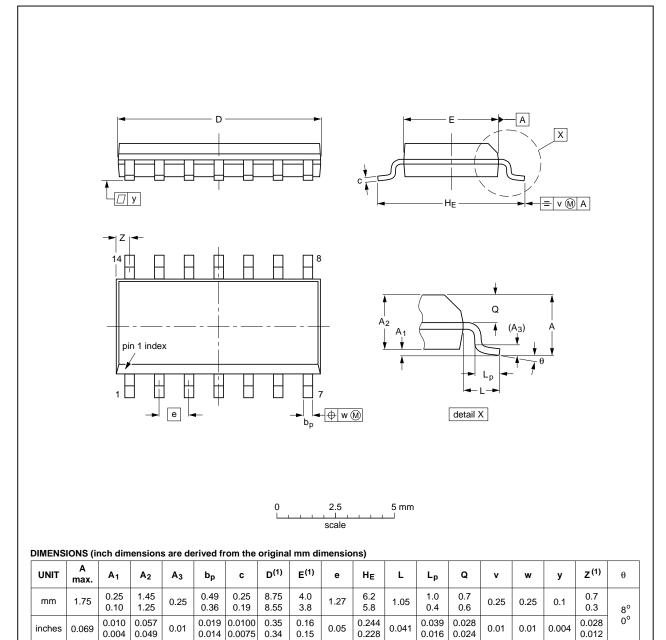
0.33

Fig 7. Package outline SOT27-1 (DIP14)

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SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN	ISSUE DATE
	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT108-1	076E06	MS-012				99-12-27 03-02-19

Fig 8. Package outline SOT108-1 (SO14)

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14. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
HEF4024B v.7	20111118	Product data sheet	-	HEF4024B v.6
Modifications:	 Legal page 	s updated.		
	 Changes in 	"General description" and "I	Features and benefits".	
	• <u>Table 1</u> , de:	scription below table title: +1	25 °C changed to +85 °	°C.
HEF4024B v.6	20111010	Product data sheet	-	HEF4024B v.5
HEF4024B v.5	20091109	Product data sheet	-	HEF4024B v.4
HEF4024B v.4	20090902	Product data sheet	-	HEF4024B_CNV v.3
HEF4024B_CNV v.3	19950101	Product specification	-	HEF4024B_CNV v.2
HEF4024B_CNV v.2	19950101	Product specification	-	-

15. Legal information

15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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- [2] The term 'short data sheet' is explained in section "Definitions"
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